Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,318	MUI ET AL.	
Examiner	Art Unit	
Eric B. Chen	1765	

SEARCHED					
Class	Subclass	Date	Examiner		
430	5	6/21/2005	EC		
438	5,9,14,16	6/21/2005	EC		
438	714	6/21/2005	EC		
438	719-721	6/21/2005	EC		
438	723,724	6/21/2005	EC		
438	740,743	6/21/2005	EC		
438	744	6/21/2005	EC		
216	60,67,70	6/21/2005	EC		

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
Performed inventor search for double patenting	6/20/2005	EC
EAST search	6/21/2005	EC
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